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## **STARC Collaborates with Atrenta on EDA Tool Quality Management System**

Yokohama, Japan Jan. 27, 2010 — the Semiconductor Technology Academic Research Center (STARC) and Atrenta Inc. today announced a collaboration to develop an EDA Tool Quality Management System. This system is based on a QA Data Base provided by STARC and expands the ongoing quality monitoring of Atrenta's SpyGlass<sup>®</sup> RTL platform.

As part of this collaboration, STARC has provided regression test specifications and a rich set of design test cases to Atrenta. Atrenta then integrated these tests into their SpyGlass platform regression test suite, enabling a detailed measurement of quality and production readiness of SpyGlass platform releases. Atrenta provides a QA Report to STARC including regression test results, types of bugs found, and resolutions implemented before the target release.

“We have been working with Atrenta for one and a half years to implement this scheme. The production quality of the SpyGlass family has allowed us to make good progress,” said Nobuyuki Nishiguchi, vice president and general manager at STARC. “STARC can provide leading edge front-end design methodologies to our client companies more easily through this collaboration. Our client companies are now able to deploy new releases of SpyGlass very efficiently.”

“The QA Data Base is an effective way to implement improved quality procedures because it is authorized by all STARC clients and has been developed based on real world design issues,” said Mike Gianfagna, vice president of marketing at Atrenta. “We have been enhancing our software regression suite through the customer test case access program (CTAP), and this collaboration with STARC is a valuable addition. Through this collaboration, we can accelerate distribution of high quality products to STARC clients that facilitate Early Design Closure®.”

Atrenta and STARC plan to expand this scheme to other product families to allow continuous improvement of product quality and reduction of adoption and deployment costs for STARC member companies.

### **About STARC**

The Semiconductor Technology Academic Research Center, STARC, is a research consortium co-founded by major Japanese semiconductor companies in December 1995. STARC's mission is to contribute the growth of the Japanese semiconductor industry by developing leading-edge SoC design technologies.

For more information, please visit <http://www.starc.jp/index-e.html>

### **About Atrenta**

Atrenta is the leading provider of Early Design Closure® solutions to radically improve design efficiency throughout the IC design flow. Customers benefit from Atrenta tools and methodologies to capture design intent, explore

implementation alternatives, validate RTL and optimize designs early, before expensive and time-consuming detailed implementation. With over 150 customers, including the world's top 10 semiconductor companies, Atrenta provides the most comprehensive solution in the industry for Early Design Closure. For more information, visit [www.atrenta.com](http://www.atrenta.com). Atrenta, Right from the Start!

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